Identifying contact e ects in electronic conduction through buckyballs on silicon

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We present a theory of current conduction through buckyball (C $_{60}$) molecules on silicon by coupling a density functional treatment of the molecular levels embedded in silicon with a non-equilibrium G reen's function (NEGF) treatment of quantum transport. Several experimental variations in conductance-voltage (G-V) characteristics are quantitatively accounted for by varying the detailed molecule-silicon bonding geometries. We identify how variations in contact surface microstructure in uence the number, positions and shapes of the conductance peaks, while varying separations of the scanning probe from the molecules in uence their peak amplitudes.

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M olecular electronics represents an ultim ate dream for nanoscale m aterial and device engineering. A long with well characterized, reproducible experiments, quantitative m odels for m olecular conduction are crucial for a proper understanding and benchm arking of this em erging

eld, and for the exploration of novel device paradigm s. A persistent problem has been incom plete know ledge of m etal contact m icrostructures and their in uence on conduction. In this respect, a sem iconducting substrate provides a superior test-bed due to its well studied surface chem istry for transport m easurem ents [1, 2]. It is therefore worthwhile to develop and re ne our know ledge base using a fam iliar m olecule bonded on a well-characterized silicon substrate that leaves little wiggle room for theory.

Am ong various molecules probed using scanning tunneling spectroscopy (STS), buckyball (C₆₀) molecules stand out for their unique well calibrated bandstructure, alkalim etaldoped superconductivity, switching and optoelectronic properties [3]. A lthough STS studies of buckyballs on metals have allowed detailed comparison with theory [4], they do not reveal much information about their underlying contact microstructure. In contrast, buckyballs on silicon exhibit considerable variation in their G-V characteristics depending on the nature of their covalent bondings with the surface dimers [5, 6, 7, 8].

In this paper, we explore conduction through buckyballs on silicon, and correlate observed variations in their G-Vs with variations in their contact bonding geometries (Fig. 1). A variation in the nature of the moleculesubstrate bonding leads to a variation in the number and shapes of conductance peaks, while a variation in the tipsam ple tunneling gap leads to a variation in the relative peak heights. Our theoretical formulation thus serves a dual purpose: on one hand, it tests our quantitative model for molecular conduction, in particular on a sophisticated sem iconducting substrate; on the other hand, it provides useful insights that allow us to deconstruct the role of contact geom etry on molecular conduction.

Theoretical technique. We calculate molecular conduction by coupling an electronic structure calculation for the molecule and the contacts with a treatment of quan-

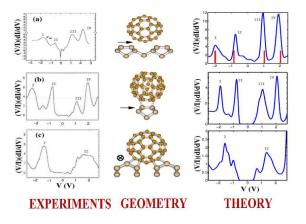


FIG.1: D i erent STS m easurem ents [5, 6] on C₆₀ m olecules docked onto Si(100) 2 1 surface (left panel). We attribute di erent bonding geom etries (m iddle panel) for each experiment, leading to a theoretical G-V (right panel) that agrees quite well with the corresponding m easurem ent. The arrow represents the dimer direction of the reconstructed surface (cross going into the page). The upper geom etry corresponds to C₆₀ physisorbed on four surface dimers, the m iddle one represents the buckyball chem ically bonded with a single surface dimer, while the bottom one has the m olecule lowered into the trough caused by a m issing dimer.

tum transport using NEGF [9, 10]. The C₆₀ structure and H am iltonian are obtained using density functional theory within the local density approximation (LDA). The reconstructed surface geometry of Si(100) is obtained by LDA optimization with a norm-conserving pseudopotential in a plane-wave basis [11]. Although it is possible in principle to describe the silicon bandstructure using DFT, as has been custom arily done in the past form etal substrates [10, 12], adapting the same process to sem iconductors is quite challenging, given the com plicated bandstructure, extended band-bending and incom plete screening, reconstruction, and surface chem – istry of silicon. Fortunately, within the NEGF form alism one can form ally partition the problem so that the only quantum e ect of the silicon substrate that the molecule

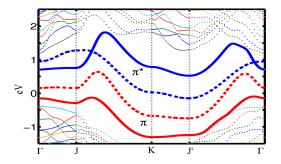


FIG. 2: Calculated surface bandstructure of asym m etric dim er (solid lines) and sym m etric dim er (dashed lines) reconstructions along Si(100)-2x1 using EHT bulk Siparam eters [14] and optim ized surface geom etries [11].

is sensitive to resides in its surface G reen's function. In the past, we developed a technique for combining di erent electronic structure codes by m atching their interfacialG reen's functions expressed in two di erent atom istic basis sets. The m atch is exact for two equally complete basis sets and a best- t otherw ise, and only assum es local separability of their one-electron potentials [2, 13].

We use an Extended Huckel (EHT) type model param etrized by Cerda et. al. [14] to generate a good quantitative description of the bulk silicon bandstructure (calibrated with LDA+GGA calculations), and also the surface band structure of 2 1 reconstructed Si-(100) (calibrated with experim ents and GGA calculations [15]). To check the properties of Si(100)-2x1 reconstructed surface properly, a slab of 13 silicon layers with a hydrogenpassivated bottom layer is used to simulate the bandstructure of Si(100)-2x1 asym m etric dim er (AD) reconstruction and symmetric dimer (SD) reconstruction. The red and blue solid lines in Fig 2 represent the and states of Si(100)-2x1 AD reconstruction while the dashed lines represent the corresponding and states of the SD reconstruction. The form er clearly shows a bandgap

0.6 eV while the latter shows a continuum of states in the bulk bandgap region. A fler benchmarking these properties (details will be published elsewhere), the recursive surface green's function is computed for the sem iin nite silicon substrate. We then use a mixed-basis method [13] to transfer the Si(100) surface G reen's function computed in the EHT Slater type orbital (STO) basis into a 6-31g(d) basis set that is then connected with a DFT/6-31g(d) Ham iltonian for the molecule.

W hile the molecule and substrate are modeled atomistically, we employ a simpler treatment of the STM tip using a self-energy $_2(d_0)$ [2], where d_0 is the tip to molecule bond length. More sophisticated models could be used to describe tip-sample interactions in experiments with well characterized tip structures. Vacuum tunneling is described using a typical W KB factor [16]

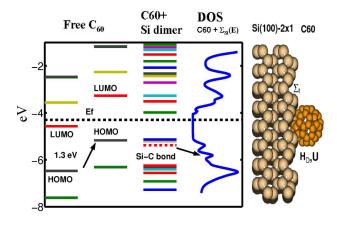


FIG. 3: Energy level alignment between C_{60} and silicon. The left panel shows the energy levels of isolated C_{60} , with the calculated Ferm i energy of the doped silicon shown as a dashed line. The C_{60} energy levels are shifted by 1.3 eV due to self-consistent charging driven by the workfunction di erence between the m olecule and the substrate, and the corresponding charge transfer from Si to C_{60} . Chem isorption creates new levels due to SiC bonds, easily seen by adding a silicon dimer to the molecule and passivating the cluster at the bottom . Finally, including the silicon self-energy amounts to adding the entire silicon substrate and generates a continuum m olecular band. The right panel shows the density of states corresponding to the geometry in the middle of Fig. 1.

premultiplying $_2(d_0)$, making the net self-energy $_2$ energy and distance dependant. Our approach includes the bias-dependent barrier prole and agrees quantitatively with measured STS spectra on bare silicon.

Equilibrium band diagram. We start by describing the silicon-buckyballbonding chem istry, band form ation, and the corresponding band alignment due to charge transfer. DFT (LSDA/6-31g) gives a good description of the energy levels for isolated C₆₀. The highest occupied molecular orbital (HOMO) is at -6.5 eV while the lowest unoccupied molecular orbital (LUMO) is at -4.6 eV relative to vacuum . Once the buckyball connects to ndoped silicon, electrons are transferred from Sito C 60 because the Ferm ilevel of Si is higher than the C $_{\rm 60}$ LUM O . Self-consistent calculations with a Hubbard-type capacitive charging energy [18] yield a net charge transfer that raises the energy levels of C₆₀ by about 1.3 eV, which is very close to the di erence in workfunction between C60 and Si. The charging energy of the Hubbard ham iltonian [19] is chosen to be 1.2 eV, consistent with experiments involving C_{60} on metal and with solid C_{60} surface [20].

Fig. 3 explains the energy level diagram using the geom etry in the middle of Fig. 1 as an example. The solid lines represent the energy levels of an isolated buckyball, while the dashed line represents the ferm i level of bulk Sicalculated from the experim entaldoping levels [5]. In addition to the charge transfer and band-alignment driven by electrostatics, there is also substantial transfer

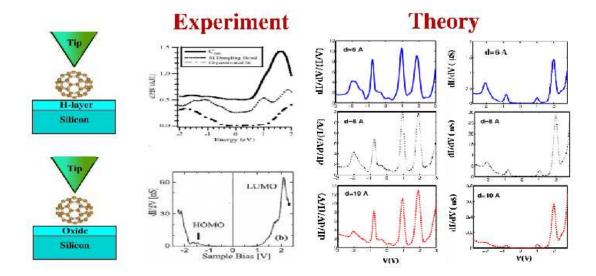


FIG.4: Introducing tunnelbarriers between the STM and the sam ple or the sam ple and the substrate (far left) de-em phasizes the HOMO levels relative to the LUMO ones due to their relatively larger barrier heights, accounting for m easurements (left) with little or no signature of HOMO levels [7, 8]. A lthough the unnom alized conductance shows this e ect with increasing tip-sam ple separation d (right), norm alizing the conductance (center) as in Fig.1 restores these peaks.

of spectral weight from Si to C₆₀ leading to the form ation of bonding-antibonding pairs. The energy levels of C₆₀ bonded with a single surface silicon dimer system shows the e ect of bonding, which leads to both level rearrangement and level creation. A wave-function plot of those levels shows a lot of hybridization between C and Si. The rightm ost panel show s the density of states of C₆₀ with the Si surface which provides the proper boundary conditions of the open system described with an energydependent self-energy. A clear peak appears between the HOMO and HOMO-1 levels in the STS (i.e., between peaks marked I and II), which we attribute to the Si-C bond arising from strong Si and C hybridization.

Results: Peak positions and heights. Fig. 1 shows the calculated G-Vs for C₆₀ docked on a clean silicon surface with di erent bonding geom etries. The conductances are norm alized using an averaging procedure adopted in the experim ental analyses [21, 22]. The upper set of gures corresponds to C 60 physisorbed on the Si (100)-2 1 surface. The bottom of the buckyball is kept 2.1 A away from the Sisurface dimerto ensure weak coupling. Under these circum stances, the STS probes the bare C_{60} electronic structure with the molecular levels (Fig. 3) generating G-V peaks marked I, II, III, and IV in Fig.1. The vertical bars in Fig. 1 denote the LDA/4-31g HOMO-1, HOMO, LUMO, and LUMO+1 levels of isolated C_{60} rigidly shifted by 1.2 eV due to charging as before, although the precise shift di ers due to the di erent Ferm i energies of the n and p-Si substrates. The excellent correspondence between the isolated C 60 levels and the conductance peaks thus gives us an elementary interpretation of the STS data in the upper geometry of Fig. 1.

The bonding geometry between C_{60} and the Si(100)

surface changes upon annealing from physisorption to chem isorption [23], corresponding to the middle and the bottom sets of plots in Fig.1. W e consider two prom inent chem isorption geom etries based on experim ental suggestions. The st consists of C₆₀ chem ically bonded with a Si surface dim er that straddles diam etrically opposite ends of a C_{60} hexagon. The experim ental dI/dV / (I/V)s m easured using STS are reproduced by our density functional conductance calculation, with the only variable being the geom etry itself. The fourm ain m arked peaks still arise from the isolated C $_{60}$ energy levels discussed above. In addition, our calculation reveals an extra sm aller peak between peaks I and II, as in the experiments. This small peak has also been observed by ultraviolet photoem ission spectroscopy (UPS) measurements on the $C_{60}/Si(100)$ -2 1 system [24]. The origin of this secondary peak is from strong covalent Si-C bonding, seen in the correlation diagram between C₆₀ and a surface Sidim er in Fig. 3 and also in the corresponding density of states.

The bottom plot of Fig. 1 shows the experimental and calculated conductances corresponding to a dierent chem isorption geometry realized upon annealing, consisting of a missing silicon dimer that causes the buckyball to drop into the empty trough [5]. It is clear from the bonding geometry (middle panel), that the closer proximity with the surface leads to the establishment of more covalent bonds, radically altering the electronic structure of bare C $_{60}$. The STS G-V in (c) is qualitatively di erent from the geometries in (a) and (b). There is one clear HOM O peak for negative substrate bias and a broadened LUM O level in the positive direction replacing the four original peaks. Our simulation captures the main features of this experiment. The original Si-C peak

goes up to become the main negative bias peak, while several additional Si-C peaks are formed near the conducting LUM O levels due to the additional bondings. In addition, our calculation generates spurious peaks from the unrelaxed C_{60} structure adopted in our calculation for convenience. We believe that strong chem isorption would deform the C_{60} near the bottom, eliminating these extra peaks by bonding-antibonding splitting. We leave a detailed study of C_{60} relaxation for future work.

In addition to the number and positions of the peaks, other experiments show variations in the conductance peak heights [6, 7, 8] (Fig. 4). A possible origin is the di ering tip-sample spacings in these experiments. A W KB treatment of tunneling through varying vacuum thicknesses provides a qualitative explanation. U sing the physisorbed geometry in Fig.1 (a) as an example, we nd that increasing the tip-sample gap from 6 A to 8 A and then to 1 nm progressively deem phasizes the role of the HOMO levels in comparison to the LUMO levels. Note however that such WKB factors are eliminated in the earlier log-norm alized dI/dV / (I/V) plots (Fig. 4), as expected [21] but show up in the unnorm alized dI/dV conductance plots (Fig. 4). From the dI/dV vsV in Fig. 4, it is very clear that the thicker barrier cuts down the HOMO contributions exponentially to within the noise levels of the experiment. Electrons tunneling from the HOMO level in the negative bias direction encounter a higher tunneling barrier than electrons from the STM

lling the LUM O higher up. The W KB approximation suggests that each peak height is reduced roughly in proportion to exp (2kd) where k represents the decay constant of the corresponding level and d is the tip-sam ple separation. We therefore believe that measurements with no clear HOM O peaks are performed with an STM tip substantially removed from the molecule. Furthermore, the experiments in Fig. 4 have an extra tunneling barrier between the molecule and the substrate (a hydrogen passivation layer in the top example and an oxide layer in the bottom [25]). This additional barrier would further de-emphasize the HOM O contributions, practically elim – inating them from the unnorm alized conductance curves.

In sum m ary, we have used C $_{60}$ on silicon to demonstrate our capacity to theoretically deconstruct the role of contact m icrostructure on m olecular conduction. The unexplained features are the peak broadenings, which should depend on coupling with the dimer and the m olecular vibrationalm odes. A treatment of vibronic scattering would indeed be worth pursuing both for its exciting physics and for further benchmarking between experimental and computationalm olecular conduction.

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